

Search Notes

Application/Control No.

10/045,191

Examiner

Steven HD Nguyen

Applicant(s)/Patent under
Reexamination

HAUCK ET AL.

Art Unit

2665

SEARCHED

Class	Subclass	Date	Examiner
370	445-447, 449-451	5/18/05	
	454-455		
	461-462		
	293		
	252		
	256-257		
710	107, 116		
	110-111		
	119, 123		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR